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energy Electron Probe Microanalysis and Scanning Electron Microscopy
5.7 Energy Dispersive X-ray Microanalysis in Scanning and Conventional Transmission Electron Microscopy5.8 X-Ray Absorption Techniques; 6 New Computerisation Methods; 6.1 Monte Carlo Simulation for X-ray Fluorescence Spectroscopy; 6.2 Spectrum Evaluation; 7 New Applications; 7.1 X-Ray Fluorescence Analysis in Medical Sciences; 7.2 Total Reflection X-ray Fluorescence for Semiconductors and Thin Films; 7.3 X-Ray Spectrometry in Archaeometry; 7.4 X-Ray Spectrometry in Forensic Research; 7.5 Speciation and Surface Analysis of Single Particles Using Electron-excited X-ray Emission Spectrometry
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Sommario/riassunto

X-Ray Spectrometry: Recent Technological Advances covers the latest developments and areas of research in the methodological and instrumental aspects of x-ray spectrometry. Includes the most advanced and high-tech aspects of the chemical analysis techniques based on x-raysIntroduces new types of X-ray optics and X-ray detectors, covering history, principles, characteristics and future trendsWritten by internationally recognized scientists, all of whom are eminent specialists in each of the sub-fieldsSections include: X-Ray Sources, X-Ray Optics, X-Ray Detectors, Spec